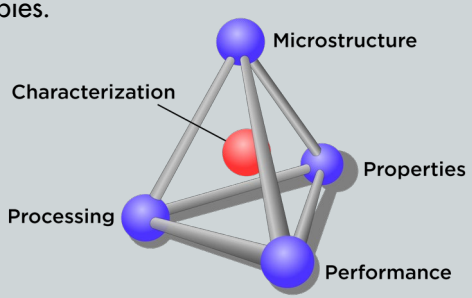
Complementary APT and SIMS for Materials Characterization

Characterization is the key

Materials are made up of infinite variations and understanding fully them often requires purposefully chosen microscopies.



Synergistic Microscopies – SIMS/APT

SIMS has strengths in sensitivity and simple specimen preparation, while APT has the strengths of nanoscale spatial resolution and the ability to analyze any combination of elements from Hydrogen to Uranium – together they can be very powerful.

Tips !

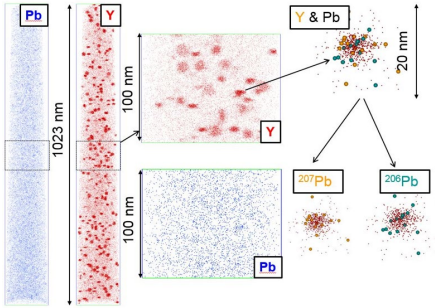
Using the right combination of techniques one can understand and optimize the modeling, microstructure, processing, and properties of materials.

Can APT and SIMS benefit from each other?

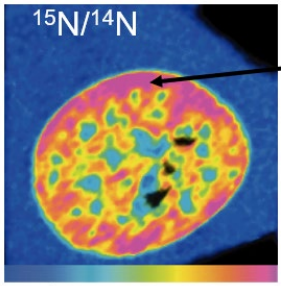
A synergetic approach between complementary techniques such as Secondary Ion Mass Spectrometry (SIMS) and Atom Probe Tomography (APT) can magnify the power of these techniques – allowing discoveries that each alone would miss.

In the webinar, the standard and cutting-edge technologies of each technique will be summarized from specimen preparation to data reduction and examples of the complimentary techniques will be discussed.









15N-thymidine

CAMECA SCIENCE & METROLOGY SOLUTIONS / AMETEK